

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10617324	GODFREY ET AL.
	Examiner GERMAN VIANA DI PRISCO	Art Unit 2617

SEARCHED

Class	Subclass	Date	Examiner
See application file for complete search history.		3/19/2008	GV

SEARCH NOTES

Search Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	3/19/2008	GV
Inventor name and Assignee search in PALM ExPO and EAST	3/19/2008	GV
IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	3/19/2008	GV
EPO Database(http://ep.espacenet.com)	3/19/2008	GV
Consulted with Rafael Perez-Gutierrez	3/19/2008	GV

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
See interference search in search history.		3/19/2008	GV